


<b>Search Notes</b>  	<b>Application/Control No.</b>  10532748	<b>Applicant(s)/Patent Under Reexamination</b>  PAVON ET AL.
	<b>Examiner</b>  Cehic, Kenan	<b>Art Unit</b>  2416

SEARCHED			
Class	Subclass	Date	Examiner
370	346,449,395.4,343,344,230	12/5/2007	KC

SEARCH NOTES		
Search Notes	Date	Examiner
Inventorship search	12/5/2007	KC
Consulted with SPE Kwang Yao	12/5/2007	KC
IEEEExplore	12/5/2007	KC
Update search	8/1/2008	kc
Update search / consult with SPE Kwang Yao	7/27/2009	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	See interference search printout	7/28/2009	kc

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